

**Search Notes****Application/Control No.**

10/773,179

**Examiner**

Emmanuel Bayard

**Applicant(s)/Patent under Reexamination**

CHEN ET AL.

**Art Unit**

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	260	3/19/2007	EB
375	261	3/19/2007	EB
375	285	3/19/2007	EB
375	295	3/19/2007	EB
375	296	3/19/2007	EB
370	208	3/19/2007	EB
370	209	3/19/2007	EB
370	210	3/19/2007	EB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/19/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner